

Class	Subclass	ISSUE CLASSIFICATION

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PATENT NUMBER

U.S. UTILITY Patent Application

SCANNED	O.I.P.E.	PATENT DATE

APPLICATION NO. 09/605293	CONT/PRIOR	CLASS 257	SUBCLASS 347	ART UNIT 281-1	EXAMINER Richard
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APPLICANTS
DAVID L. CHAPEK

TITLE
METHOD FOR CONTROLLING THE MORPHOLOGY OF DEPOSITED SILICON ON A SILICON DIOXIDE SUBSTRATE AND SEMICONDUCTOR DEVICES INCORPORATING SUCH DEPOSITED SILICON

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
INTERNATIONAL CLASSIFICATION							

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<input type="checkbox"/> TERMINAL DISCLAIMER <input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed. <input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent. No. _____ <input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	DRAWINGS Sheets Drwg. Figs. Drwg. Print Fig.			CLAIMS ALLOWED Total Claims Print Claim for O.G.	
	_____ (Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED _____	
	_____ (Primary Examiner) (Date)			ISSUE FEE Amount Due Date Paid	
	_____ (Legal Instruments Examiner) (Date)			ISSUE BATCH NUMBER _____	

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